

Search Notes

Application/Control No.

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Examiner

YONG D. PAK

Applicant(s)/Patent under
Reexamination

ALLAIN ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:2 and sequence alignment between 5 and 13	5/6/2009	YP
east (all databases): inventor and text search, see search history	5/6/2009	YP
PALM: search of all inventors	5/6/2009	YP